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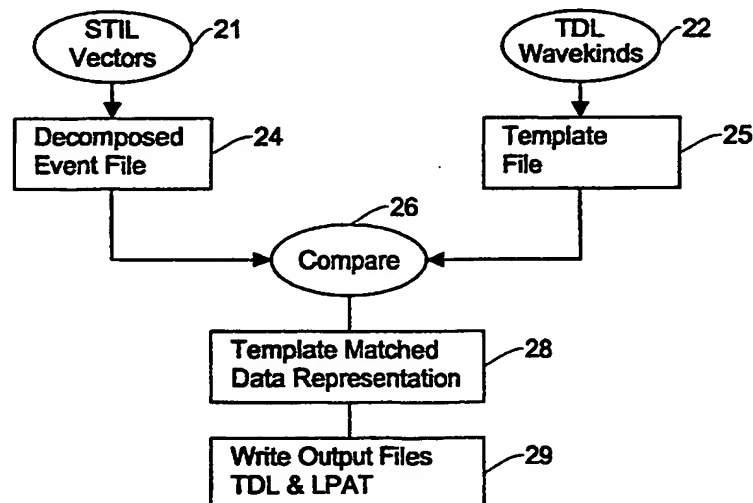
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(54) Title: TEST LANGUAGE CONVERSION METHOD



(57) Abstract: A method of converting test vectors (21) in an original test-cycle based language into a target-cycle based test language (22). The method includes the steps of forming a set of templates (25) depicting waveforms defined in the target test language (22); decomposing a waveform (24) in the original test language into a set of constituent events where each event includes data showing at least a starting value and a number of subsequent edges of the waveform; comparing the template and the set of events (26); storing the waveform data in the target test language when a match is detected (28) and retrieving corresponding parameters of the waveform in the original test language (29); and repeating the above steps for all of the test vectors in the original test language, thereby forming a test vector file of the target test language.